

Abstract of the Disclosure

[0111] A method and associated apparatus for communicating defect information between a defect source identifier server and client. The method comprises creating defect inspection information within a defect source identifier client, the defect inspection information containing information regarding identified defects on semiconductor wafers. In one aspect, an XML converter converts the defect inspection information into converted defect inspection information that is in a form defined by user defined tags. The converted defect inspection information is transmitted through a network to a defect source identifier server. Defect source information is derived at the defect source identifier server in response to the converted defect inspection information.

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